

Notice of References Cited	Application/Control No. 10/587,695		Applicant(s)/Patent Under Reexamination AKAMATSU, MASA HARU	
	Examiner Dimple N. Bodawala		Art Unit 1791	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,051,083 A	09-1991	Coluzzi, Antonio	425/174.8R
*	B	US-5,182,121 A	01-1993	Miyashita et al.	425/338
*	C	US-5,297,480 A	03-1994	Miyashita et al.	100/90
*	D	US-5,496,433 A	03-1996	Miyashita et al.	156/358
*	E	US-5,558,015 A	09-1996	Miyashita et al.	100/50
*	F	US-2005/0064054 A1	03-2005	Kasumi, Kazuyuki	425/112
*	G	US-6,994,541 B2	02-2006	Chung et al.	425/385
*	H	US-7,114,938 B2	10-2006	Chou, Stephen Y.	425/126.1
*	I	US-7,137,803 B2	11-2006	Chou, Stephen Y.	425/405.1
*	J	US-7,195,476 B2	03-2007	Ito, Hidetoshi	425/388
*	K	US-7,204,686 B2	04-2007	Chung et al.	425/385
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.